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| Notice of References Cited | Application/Control No. 09/453,918 | Applicant(s)/Patent Under Reexamination LEE ET AL. | |
| | Examiner Kenny Lin | Art Unit 2154 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------------|----------------|
| * | A | US-6,670,968 B1 | 12-2003 | Schilit et al. | 715/760 |
| * | B | US-6,865,404 B1 | 03-2005 | Tikkala et al. | 455/566 |
| * | C | US-6,128,012 A | 10-2000 | Seidensticker et al. | 345/685 |
| * | D | US-6,381,474 B1 | 04-2002 | Kraft, Christian Rossing | 455/566 |
| * | E | US-6,125,287 A | 09-2000 | Cushman et al. | 455/566 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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